

Table of Contents

Conference Committee	VII
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Preface	IX
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Key Note

Holography in the '60s and '70s – A View from the Fringes.....	2
C. M. Vest	

Topic 1: New Methods and Tools for Data Acquisition and Processing

Coherence Holography: A Thought on Synthesis and Analysis of Optical Coherence Fields (invited paper)	14
M. Takeda, W. Wang, D. N. Naik	

The Polarization Approach in Measuring Correlation Properties of Optical Fields	22
O. V. Angelsky, C. Y. Zenkova, N. V. Gorodys'ka	

Real-time Coherence Holography	28
D. N. Naik, T. Ezawa, Y. Miyamoto, M. Takeda	

Coherence and Correlation in Digital Holography.....	34
I. Yamaguchi	

Analysis of fringe formation and localization in optical interferometry using optical coherence.....	41
C. S. Narayanamurthy	

Quantitative Phase Imaging in Microscopy (invited paper)	50
C. JR. Sheppard, S. S. Kou, S. Mehta	

Comparison and unification of speckle-based phase retrieval and holography with applications in phasefront alignment and recognition	57
P. F. Almero, G. Pedrini, F. Zhang, A. M. S. Maallo, A. Anand, P. N. Gundu, W. Wang, A. Asundi, W. Osten, S. G. Hanson	
High Precision Object Phase Reconstruction with Modified Phase Retrieval.....	63
S. Förster, H. Gross	
Phase retrieval with an LCoS display: characterization and application	72
C. Kohler, F. Zhang, W. Osten	
Digital dynamic-fringe pattern processing without frequency carrier, using wideband phase-shifting algorithms.	78
J. C. Estrada, F. Mendoza-Santoyo, M. de la Torre, T. Saucedo	
Error-compensating phase-shifting Fizeau interferometry with a wavelength-tunable laser diode	87
Y. Ishii, S. Idoi, H. Fujita, H. Funamizu	
Lateral Shearing Interferometer based on a Spatial Light Modulator in the Fourier Plane	93
C. Falldorf, R. Klattenhoff, A. Gesierich, C. v. Kopylow, R. Bergmann	
Digital phase shifting holography and holographic interferometry....	99
M. Kujawińska, N. Kumar, A. Michalkiewicz	
Fourier-transform method with high accuracy by use of iterative technique narrowing the spectra of a fringe pattern	106
S. Nakayama, H. Toba, N. Fujiwara, T. Gemma, M. Takeda	
Fringe pattern processing using a new adaptive and steereable asynchronous algorithm	112
J.A. Quiroga, J.A. Gómez-Pedrero, M. Servín	
Synthetic Aperture Digital Holography (invited paper)	118
J. Rosen, B. Katz	

A new application of the Delaunay triangulation: The processing of speckle interferometry signals	123
S. Equis, P. Jacquot	
Phase analysis of interference signal with optical Hilbert transform based on orthogonal linear polarization phase shifting.....	132
V. D. Madjarova, H. Kadono, N. Kurita	
Digital Fourier-transform processing for analysis of speckle photographs.....	138
K. A. Stetson	
Wavefront evaluation in phase shifting interferometry based on recurrence fringe processing with 3D prediction.....	142
I. Gurov, A. Karpets, E. Vorobeva	
White-light fringe analysis with low-cost CCD camera	149
Z. Buchta, P. Jedlička, M. Matějka, V. Kolařík, B. Mikel, J. Lazar, O. Číp	
Design and assessment of Differential Phase-Shifting Algorithms by means of their Fourier representation	153
M. Miranda, B. V. Dorrio	
A Nonlinear Technique for Automatic Twin-Image and Zero-Order Term Suppression in Digital Holographic Microscopy	160
N. Pavillon, C. S. Seelamantula, M. Unser, C. Depeursinge	
Modified two-step phase-shifting algorithm: analysis, demonstration, and application.....	164
X.-F. Meng, X. Peng, L.-Z. Cai, A.-M. Li, J.-P. Guo, Y.-R. Wang	
The Used of Reference Wave for Diagnostics of Phase Singularities.....	170
O. V. Angelsky, A. P. Maksimyak, P. P. Maksimyak	
New convolution algorithms for reconstructing extended objects encoded in digitally recorded holograms.....	174
P. Picart, P. Tankam, D. Mounier, Z. Peng, J.-C. Li	
Reconstruction of noisy measured sharp edges at thin sheet metal components	180
J. Weickmann, A. Liedl, P.-F. Brenner, A. Weckenmann	

Reduction of speckles in digital holographic interferometry.....	184
S. Hertwig, H. Babovsky, A. Kiessling, R. Kowarschik	
Normalization and denoising in a multi-source and multi-camera profilometric system	189
E. Stoykova, A. Gotchev, V. Sainov	
Automated Phase Map Referencing Against Historic Phase Map Data	193
R. M. Groves, D. Derauw, C. Thizy, I. Alexeenko, W. Osten, M. Georges, V. Tornari	
Numerical multiplexing and de-multiplexing techniques for efficient storage and transmission of digital holographic information.....	197
M. Paturzo, P. Memmolo, A. Tulino, A. Finizio, L. Miccio, P. Ferraro	
Fringe Pattern Normalization Using Bidimensional Empirical Mode Decomposition and the Hilbert Transform	201
M. B. Bernini, A. Federico, G. H. Kaufmann	
Complementary Filtering Approach to Enhance the Optical Reconstruction of Holograms from a Spatial Light Modulator	205
M. Agour, C. Falldorf, C. von Kopylow	
Combination of Phase Stepping and Fringe Tracking to Evaluate Strain from Noisy DSPI Data	211
E. Hack	
Influence of filter operators on 3D coordinate calculation in fringe projection systems.....	215
C. Bräuer-Burchardt, M. Heinze, C. Munkelt, P. Kühmstedt, G. Notni	
Polarization interferometry of singular structure of organic crystal polarization properties.	221
S.B. Yermolenko, M.P. Gorsky, Y. A. Ushenko, A.G. Pridiy	
Zero order interferometry technique for measuring the Lyapunov's maximal index in optical fields	225
M. S. Gavrylyak, A. P. Maksimyak, P. P. Maksimyak	
Orientation-selective spiral-phase contrast microscopy.....	230
G. Situ, M. Warber, G. Pedrini, W. Osten	

Topic 2: Application Enhanced Technologies

Model-based white light interference microscopy for metrology of transparent film stacks and optically-unresolved structures (invited paper)	236
P. de Groot, X. Colonna de Lega, J. Liesener	
Limitations and Optimization of Low-coherence Interferometry for High Precision Microscopic Form Measurement	244
P. Lehmann, J. Niehues	
Instantaneous Wavelength Detection by a Whole-Field k-space Method	250
A. Davila, J. M. Huntley, P. D. Ruiz, J. M. Coupland	
Limiting aspects in length measurements by interferometry	256
R. Schödel	
Aspects of design and the characterization of a high resolution heterodyne displacement interferometer	263
C. Weichert, J. Flügge, R. Köning, H. Bosse, R. Tutsch	
The femtosecond optical synthesizer as a tool for determination of the refractive index of air in ultra-precise measurement of lengths.....	269
O. Cip, R. Smid, B. Mikel, M. Cizek, B. Ruzicka, J. Lazar	
Digital holographic microscopy with a simultaneous phase-shifting interferometer for measuring the angular spectrum generated by micro-optical structures (invited paper)	275
B. Lee, J. Hahn, Y. Lim, H. Kim, E.-H. Kim	
Resolution enhancement in digital holography by a two-dimensional electro-optically tunable phase grating	283
M. Paturzo, A. Finizio, S. De Nicola, P. Ferraro	
Resolution improvement in lensless digital holographic interferometry	289
D. Claus, M. Fritzsche, B. Timmerman, P. Bryanston-Cross	
Digital holography catching up with analogue holography both in resolution and in field of view with a bottom-line camera	298
F. Gyimesi, V. Borbély, Z. Füzessy, B. Ráczkevi	

Fresnel and Fourier digital holography architectures: a comparison.	304
D. P. Kelly, D. S. Monaghan, N. Pandey, B. M. Hennelly	
The last Word on Three-Flat Calibration – are we there yet?	309
J. Burke, B. Oreb	
A New Flatness Reference Measurement System Based on Deflectometry and Difference Deflectometry	318
G. Ehret, M. Schulz, M. Stavridis, C. Elster	
Quasi absolute Test for Aspherics via dual Wavefront Holograms and a radial Shear Position	324
K. Mantel, I. Harder, E. Geist, N. Lindlein	
Rapid and flexible measurement of precision aspheres	330
E. Garbusi, G. Baer, C. Pruss, W. Osten	
Measurement of the shape of objects by the interferometry with two wavelengths	339
P. Pavlicek, G. Häusler	
Recording-plane division multiplexing (RDM) in pulsed digital holography for optical metrology	345
X. Wang, C. Yuan, H. Zhai	
Identification of deformation components in TV holography and digital holography	350
J. Kornis, R. Séfel	
Extending the capabilities of the sphere interferometer of PTB by a stitching procedure	354
G. Bartl, A. Nicolaus	
Fringe contrast improving in low coherence interferometry by white light emitting diodes spectrum shaping	358
A. Pakula, L. Salbut	
Absolute testing of aspherics in transmitted light using an amplitude DOE.....	364
A. Berger, K. Mantel, I. Harder, N. Lindlein	

MEMS Calibration Standards for the Optical Measurement of Displacements.....	369
J. Gaspar, M. E. Schmidt, G. Pedrini, W. Osten, O. Paul	

About the feasibility of nearfield-farfield transformers based on optical metamaterials	375
S. Maisch, P. Schau, K. Frenner, W. Osten	

Analogy of white-light interferometry and pulse shaping.....	384
R. Berger, W. Osten	

Topic 3: 4D Optical Metrology over a Large Scale Range

Nanomeasuring and Nanopositioning Engineering (invited paper)..	390
G. Jäger, E. Manske, T. Hausotte, H.-J. Büchner	

Reconstruction of Shape using Gradient Measuring Optical Systems.....	398
J. Seewig, T. Damm, J. Frasch, D. Kauven, S. Rau, J. Schnebele	

Metrological SPM with positioning controlled by green light interferometry	405
J. Lazar, P. Klapetek, O. Číp, M. Čížek, J. Hrabina, M. Šerý	

Measuring Shape and Surfaces down to the Nanometer and Nanosecond scales by Digital Holographic Microscopy	411
C. Depeursinge, I. Bergoënd, N. Pavillon, J. Kühn, T. Colomb, F. Montfort, E. Cuche, Y. Emery	

Deflectometry: 3D-Metrology from Nanometer to Meter	416
G. Häusler, M. C. Knauer, C. Faber, C. Richter, S. Peterhänsel, C. Kranitzky, K. Veit	

3-D Sensing for Microstructures Using Dynamic DOEs	422
S. Dong, X. Peng, Y. Guan, A. Li, Y. Yin, J. Tian	

Doppler phase-shift fringe analysis and digital holography using high-speed digital camera	428
T. Yatagai, D. Barada	

Shape and Deformation Measurement of Moving Object by Sampling Moiré Method.....	433
Y. Morimoto, M. Fujigaki, A. Masaya, K. Shimo	
New Interferometry Tools for AeroOptics	439
J. Trolinger, V. Markov	
Dynamic Fizeau Interferometers.....	445
B. Kimbrough, B. Medower, J. Millerd	
Surface contouring of vibrating objects using quadrature transform	455
R. Legarda-Saenz, R. Rodriguez-Vera, J. A. Rayas	
Development and Application of a 10 Hz Nd:YAG Double Pulse Laser for Vibration Measurements with Double Pulse ESPI.....	461
E. H. Nösekabel, W. Honsberg, R. Kelnberger	
Combining novel fringe analysis and photogrammetry for industrial shape measurement	467
Y. R. Huddart, J. D. R. Valera, A. J. Moore	
Digital holographic interferometry for deformation measurement by means of an acoustical device	472
H. Fischer, R. Tutsch	
Pump-probe interference microscope observation for femtosecond-laser induced phenomena.....	477
Y. Hayasaki, A. Takita, M. Isaka	
Three-dimensional shape measurement of dynamic objects with spatially isolated surfaces.....	481
Q. Zhang, X. Su, L. Xiang	
Optical design of a DOE-based laser interferometer for inspection of MEMS/MOEMS	485
M. Józwik, M. Kujawińska, U. D. Zeitner, K.H. Haugholt	
Time Resolved High Resolution Shape and Colour Measurement using Fringe Projection	489
Z. Zhang, D. P. Towers, C. E. Towers	

Dynamic 3-D shape measurement techniques with marked fringes tracking.....	493
X. Su, Q. Zhang, Y. Xiao, L. Xiang	
Optical measurement and color map projection system to highlight geometrical features on free form surfaces	497
T. L. Pinto, A. V. Fantin, C. A. Carvalho, A. Albertazzi	
Digital holographic recording of large scale objects for metrology and display	501
T. Meeser, S. Huferath-von Lüpke, T. Kreis	
Multiwavelength laser interferometry	505
B. Mikel, M. Cizek, Z. Buchta, J. Lazar, O. Cip	
Accurate and fast three-dimensional imaging with use of fringe projection profilometry	509
A. Li, X. Peng, Y. Yin, Y. Guan, X. Liu	
3D vibration analysis of granular materials with two-color digital Fresnel holography	513
P. Tankam, P. Picart, D. Mounier, J.-P. Boileau, V. Tournat, V. Gusev	
System for transient spatio-temporal (4D) vibration imaging and non-destructive inspection	519
J. M. Kilpatrick, A. Apostol, V. Markov	
Microelements vibration measurement using quasi-heterodyning method and smart-pixel camera	523
A. Styk, M. Kujawińska, P. Lambelet, A. Røyset, S. Beer	
Dynamic multipoint vibrometry using spatial light modulators	528
F. Schaal, M. Warber, C. Rembe, T. Haist, W. Osten	

Topic 4: Hybrid Measurement Techniques

Optoelectronic method for device characterization and experimental validation of operational performance (invited paper)	534
R. J. Pryputniewicz	

Computational inverse holographic imaging: toward perfect reconstruction of wavefield distributions	542
V. Katkovnik, A. Migukin, J. Astola	
Cooperative Sensor Approach for holistic geometrical Measurement Tasks on Cutting Tools.....	550
A. Weckenmann, L. Shaw	
View Planning for 3D Reconstruction using Time-of-Flight Camera Data as a-priori Information	556
C. Munkelt, M. Trummer, P. Kuehmstedt, J. Denzler, G. Notni	
Stereo vision based approach for extracting features from digital holograms	562
T. Pitkääho, T. J. Naughton	
Flexible Combination of Optical Metrology Strategies for the Automated Assembly of Solid State Lasers	568
R. Schmitt, A. Pavim	
A Numerical Simulation Benchmark of Tilt Scanning Interferometry for 3D Metrology.....	572
G. E. Galizzi, P. D. Ruiz, G. H. Kaufmann	
A virtual telecentric fringe projection system	576
K. Haskamp, M. Kästner, E. Reithmeier	
Inspection of an extended surface by an active 3D multiresolution technique.....	580
J. Vargas, R. Restrepo, J. A. Quiroga, T. Belenguer	
Automated Multiscale Measurement System for micro optical elements	584
W. Lyda, A. Burla, T. Haist, J. Zimmermann, W. Osten, O. Sawodny	
Simulation based sensitivity analysis and optimization of Scatterometry measurements for future semiconductor technology nodes	592
V. Ferreras Paz, T. Schuster, K. Frenner, W. Osten, L. Sziksai, M. Mört, C. Hohle, H. Bloess	

Electronic Speckle Pattern Interferometry at Long Infrared Wavelengths. Scattering Requirements	596
J.-F. Vandenrijt, C. Thizy, I. Alexeenko, I. Jorge, I. López, I. S. de Ocáriz, G. Pedrini, W. Osten, M. Georges	

Topic 5: New Optical Sensors and Measurement Systems

Novel interferometric measurement systems for the characterization of micro-optics (invited paper)	602
H. Ottevaere, H. Thienpont	

Design of a micro-optical low coherent interferometer array for the characterisation of MEMS and MOEMS	611
K. Gastinger, K. H. Haugholt, A. Røyset, J. Albero, U. Zeitner, C. Gorecki	

Looking for a new generation of MEMS-type confocal microscopes	618
C. Gorecki, S. Bargiel, K. Laszczyk, J. Albero, J. Krezel, M. Kujawinska	

Radial in-plane achromatic digital speckle pattern interferometer using an axis-symmetrical diffractive optical element.....	622
A. Albertazzi, M. R. Viotti, W. A. Kapp	

Wavefront Sensor Design based on a Micro-Mirror Array for a High Dynamic Range Measurement at a High Lateral Resolution	628
R. Schmitt, I. Jakobs, K. Vielhaber	

Intellectual property in industry and academia: where interests merge? (invited paper)	634
N. Reingand, W. Osten	

Moiré interferometer for surface mapping with liquid crystal grids.....	648
J. A.N. Buytaert, J. J.J. Dirckx	

High resolution tilt scanning interferometry system for full sensitivity depth-resolved displacement measurements in weakly scattering materials	656
B. S. H. Burlison, P. D. Ruiz, J. M. Huntley	

Multifunctional phase-stepping interferometer for measurement in real time	662
V. Sainov, E. Stoykova	
A Wonderful World of Holography, Interferometry, and Optical Testing (honorary lecture)	670
J. C. Wyant	
Multifunctional Encoding System for Assessment of Movable Cultural Heritage	680
V. Tornari, E. Bernikola, K. Hatziyannakis, W. Osten, R. M. Grooves, M. Georges, T. Cedric, G. M. Hustinx, J. Rochet, E. Kouloumpi, M. Doulgeridis, T. Green, S. Hackney	
Investigation of electronic PCB component with two-color digital holographic interferometry	688
P. Tankam, D. Mounier, E. Moisson, P. Picart	
Integrated Microinterferometric Sensor	693
J. Krężel, M. Kujawińska	
High Precision Measurement of plane-parallel Parts.....	697
M. Fleischer, T. Gnausch, D. Supp, J. Becker	
Lateral Shearing Interferometry with Simultaneous Detection of both Gradient Fields on a Common Detector Grid	701
V. Nercissian, N. Lindlein	
Near infrared large aperture (24 inches) interferometer system development.....	705
R. Zhu, L. Chen, Z. Gao, Y. He, Q. Wang, R. Guo, J. Li, S. Deng, J. Ma	
Interior Geometry Inspection Using Rerouted Fringe Projection	709
O. Abo-Namous, M. Kästner, E. Reithmeier	
A Cellular Force Microscopic System for Cell Mechanics Investigation	713
J. Fang, J. Y. Huang, C. Y. Xiong	

Candle flame analysis by digital three-wavelength holographic interferometry	717
J.-M. Desse, P. Picart, P. Tankam	
Moiré fringe generation and phase shifting using a consumer product LCD projector	721
J. J.J. Dirckx, J. A.N. Buytaert, S. A.M. Van der Jeught	
Speckle velocimetry for high accuracy and multi-dimensional odometry	726
T. Charrett, R. P. Tatam	
Determination of Refractive Index Changes in Biconical Optical Fiber Taper	730
K. A. Stasiewicz, R. Krajewski, M. Kujawińska, L. R. Jaroszewicz	
Prosthodontic crown mechanical integrity study using Speckle Interferometry	734
P. Slangen, S. Corn, M. Fages, F. J.G. Cuisinier	
Monitoring of Drying Process of Paints using Lensless Fourier Transform Digital Holography	738
C. Shakher, G. Sheoran	
On the Digital Holographic Interferometry of Fibrous Materials: Opto-Mechanical Properties of Fibres	743
K. Yassien, M. Agour, C. von Kopylow	
Geometrical camera calibration using lasers and diffractive optical elements	747
M. Bauer, D. Griebbach, A. Hermerschmidt, S. Krüger, M. Scheele, A. Schischmanow	
Measurement of the local displacement field produced by a microindentation using speckle interferometry. Its application to analyse coating adhesion	751
A. E. Dolinko, G. H. Kaufmann	
Space-Time Multiplexing in a Stereo-photogrammetry Setup	755
M. Große, R. Kowarschik	

Interference Investigation of Concrete Structure and Dynamics During Hydration.	760
M. P. Gorsky, P. P. Maksimyak, A. P. Maksimyak	
Off-axis Reconstruction Method for Displacement and Strain Distribution Measurement with Phase-Shifting Digital Holography.....	764
M. Fujigaki, K. Shiotani, R. Nishitani, A. Masaya, Y. Morimoto	
“Flying Triangulation”: A motion-robust optical 3D sensor principle.....	768
S. Ettl, O. Arold, P. Vogt, O. Hybl, Z. Yang, W. Xie, G. Häusler	
Laser direct writing of high resolution structures on curved substrates: evaluation of the writing precision	772
M. Häfner, R. Reichle, C. Pruss, W. Osten	
 Tutorial	
Scanning Holography – A tutorial	778
T.-C. Poon	
 Appendix: New Products.....	787

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